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Supplementary Information for

Optimization of Porous Silicon Conditions for DNA-Based Biosensing via Reflectometric Interference Spectroscopy

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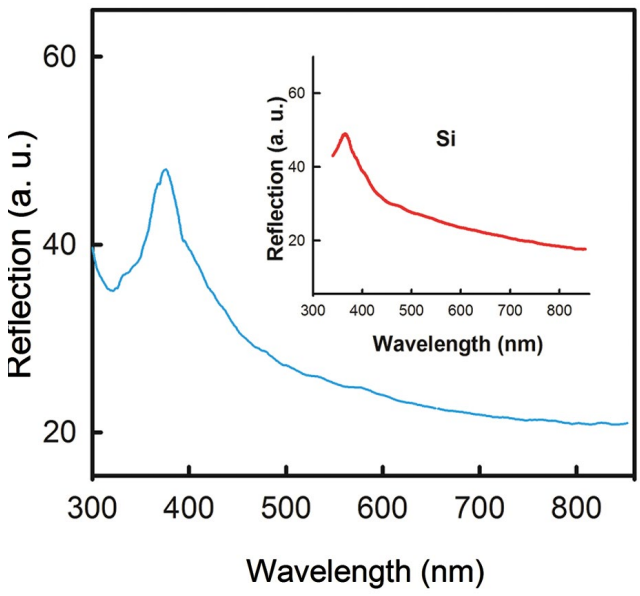

Fig.S1: Reflectance spectrum of sample 2D (inset: the reflectance spectrum of the silicon substrate).

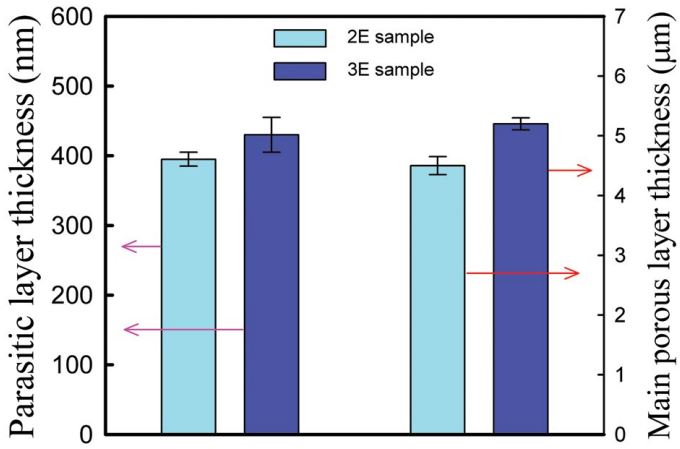

Fig.S2: Quantification of the thickness of the parasitic and main layers in samples 2E and 3E.

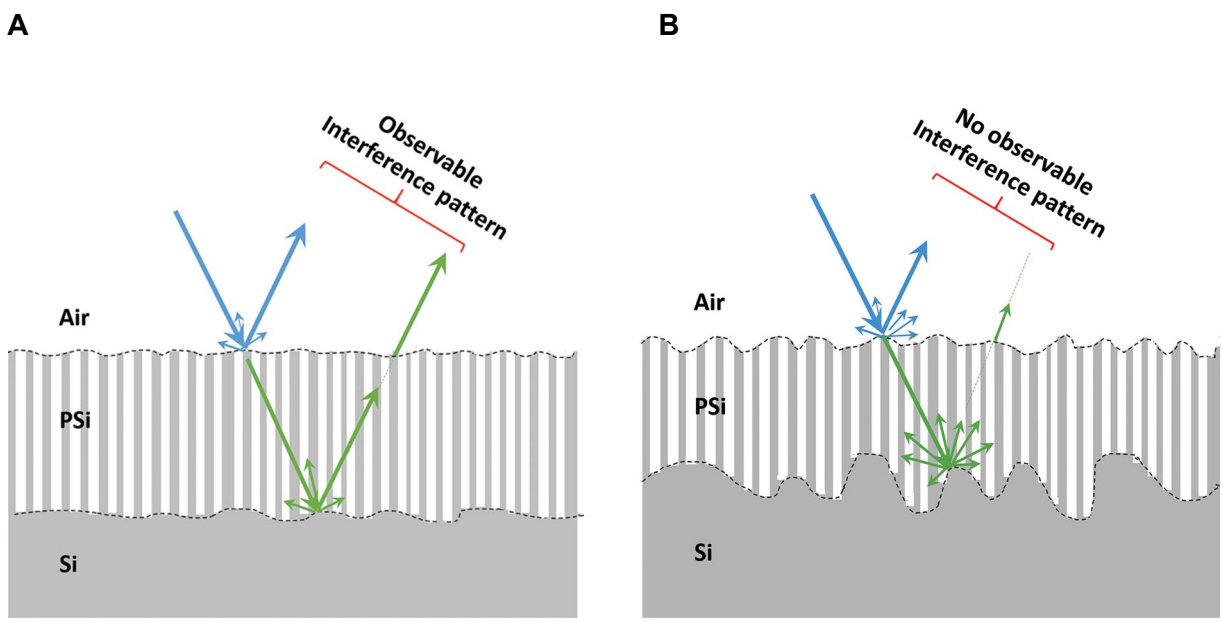

Fig.S3: The effect of surface roughness on reflection from the PSi thin film. **A.** small interface roughness and **B.** large interface roughness.